











TXS0102

## ZHCSHK3I - JANUARY 2007 - REVISED OCTOBER 2018

# 适用于漏极开路和推挽应用的 TXS0102 2 位双向电压电平 转换器

## 1 特性

- 无需方向控制信号
- 最大数据速率
  - 24Mbps (推挽)
  - 2Mbps (开漏)
- 采用德州仪器的 NanoStar™封装
- A 端口支持 1.65V 至 3.6V 的电压, B 端口支持 2.3V 至 5.5V 的电压 (V<sub>CCA</sub> ≤ V<sub>CCB</sub>)
- V<sub>CC</sub> 隔离特性:如果任何一个 V<sub>CC</sub> 输入接地 (GND),则两个端口均处于高阻抗状态
- 无需电源定序: V<sub>CCA</sub> 或 V<sub>CCB</sub> 均可优先斜升
- Ioff 支持局部关断模式运行
- 闩锁性能超出 JESD 78 Ⅱ 类规范要求的 100mA
- 静电放电 (ESD) 保护性能超过 JESD 22 规范的要求

#### - A端口:

- 2500V 人体放电模型 (A114-B)
- 250V 机器放电模式 (A115-A)
- 1500V 充电器件模型 (C101)

#### - B端口:

- 8kV 人体放电模型 (A114-B)
- 250V 机器放电模式 (A115-A)
- 1500V 充电器件模型 (C101)

#### 2 应用

- I<sup>2</sup>C/SMBus
- UART
- 通用输入/输出 (GPIO)

## 3 说明

此两位同相转换器是一个双向电压电平转换器,可用来在混合电压系统之间建立数字开关兼容性。它使用两个独立的可配置电源轨,其中A端口支持1.65V至3.6V工作电压范围,同时可跟踪V<sub>CCA</sub>电源,而B端口支持2.3V至5.5V工作电压范围,同时可跟踪V<sub>CCB</sub>电源。因此,该器件能够支持更低及更高的逻辑信号电平,同时能够在1.8V、2.5V、3.3V和5V电压节点之间任意进行双向转换。

当输出使能端 (OE) 输入为低电平时,所有输入/输出均处于高阻抗状态,从而显著减少了电源静态电流消耗。

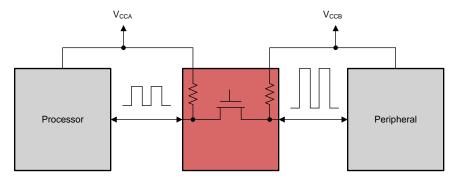
为确保在上电或掉电期间均处于高阻抗状态,应将 OE 通过下拉电阻器接地;该电阻其的最小值取决于驱动器的拉电流能力。

器件信息(1)

	11日11日115	
器件型号	封装	封装尺寸 (标称值)
TXS0102DCT	SSOP (8)	2.95mm × 2.80mm
TXS0102DCU	超薄小外形尺寸 封装 (VSSOP)(8)	2.30mm x 2.00mm
TXS0102DQE	X2SON (8)	1.40mm x 1.00mm
TXS0102DQM	X2SON (8)	1.80mm × 1.20mm
TXS0102YZP	DSBGA (8)	1.90mm × 0.90mm

(1) 如需了解所有可用封装,请参阅数据表末尾的可订购产品附录。

#### TXS0102 典型应用方框图

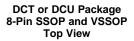


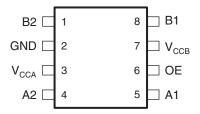


T历史记录 2 Configuration and Functions 3 cifications 4	9	8.4 Device Functional Modes	10
cifications4	9		
		Application and Implementation	
		9.1 Application Information	
Absolute Maximum Ratings4		9.2 Typical Application	
ESD Ratings4	10	Power Supply Recommendations	
Recommended Operating Conditions5	11	Layout	
Thermal Information5		· · · · · · · · · · · · · · · · · · ·	
Electrical Characteristics6			
Timing Requirements: V <sub>CCA</sub> = 1.8 V ±0.15 V 7	12		
Timing Requirements: V <sub>CCA</sub> = 2.5 V ± 0.2 V 7			
Timing Requirements: $V_{CCA} = 3.3 \text{ V} \pm 0.3 \text{ V} \dots 7$			
Switching Characteristics: $V_{CCA} = 1.8 \text{ V} \pm 0.15 \text{ V} \dots 8$			
Switching Characteristics: V <sub>CCA</sub> = 2.5 V ± 0.2 V 9			
Switching Characteristics: $V_{CCA} = 3.3 \text{ V} \pm 0.3 \text{ V} 10$			
2 Typical Characteristics			
ailed Description14	13	机倾、封农和刊 月 购	2
历史记录 本的页码可能与当前版本有所不同。			Page
April 2010) to Kevision 1			ı ayı
rom Revision G (January 2018) to Revision H			Page
d TXS0102 Lavout Example diagram			19
	Thermal Information	Thermal Information	Thermal Information



## 5 Pin Configuration and Functions

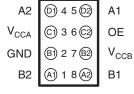




#### DQE or DQM Package 8-Pin X2SON Top View



#### YZP Package 8-Pin DSBGA Bottom View



#### **Pin Functions**

	I	PIN			
NAME		NO.		TYPE(1)	DESCRIPTION
NAIVIE	DCT, DCU	DQE, DQM	YZP		
B2	1	6	A1	I/O	Input/output B. Referenced to V <sub>CCB</sub> .
GND	2	4	B1	_	Ground
$V_{CCA}$	3	1	C1	Р	A-port supply voltage. 1.65 V ≤ V <sub>CCA</sub> ≤ 3.6 V and V <sub>CCA</sub> ≤ V <sub>CCB</sub>
A2	4	3	D1	I/O	Input/output A. Referenced to V <sub>CCA</sub> .
A1	5	2	D2	I/O	Input/output A. Referenced to V <sub>CCA</sub> .
OE	6	5	C2	I	Output enable (active High). Pull OE low to place all outputs in 3-state mode. Referenced to $V_{\text{CCA}}$ .
V <sub>CCB</sub>	7	8	B2	Р	B-port supply voltage. 2.3 V ≤ V <sub>CCB</sub> ≤ 5.5 V
B1	8	7	A2	I/O	Input/output B. Referenced to V <sub>CCB</sub> .

(1) I = input, O = output, I/O = input and output, P = power



## 6 Specifications

## 6.1 Absolute Maximum Ratings

over recommended operating free-air temperature range (unless otherwise noted) (1)

		MIN	MAX	UNIT
Supply voltage range, V <sub>CCA</sub>		-0.5	4.6	V
Supply voltage range, V <sub>CCB</sub>		-0.5	6.5	V
Input voltage range, V <sub>1</sub> <sup>(2)</sup>	A port	-0.5	4.6	V
input voltage range, viv	B port	-0.5	6.5	V
Valtage range applied to any output in the high impedance or never off state V (2)	A port	-0.5	4.6	V
Voltage range applied to any output in the high-impedance or power-off state, $V_0^{(2)}$	B port	-0.5	6.5	V
Valtage range applied to any output in the high ar law state V (2)(3)	A port	-0.5	$V_{CCA} + 0.5$	V
Voltage range applied to any output in the high or low state, $V_0^{(2)(3)}$	B port	-0.5	$V_{CCB} + 0.5$	V
Input clamp current, I <sub>IK</sub>	V <sub>I</sub> < 0		<b>-</b> 50	mA
Output clamp current, I <sub>OK</sub>	V <sub>O</sub> < 0		<b>-</b> 50	mA
Continuous output current, I <sub>O</sub>			±50	mA
Continuous current through V <sub>CCA</sub> , V <sub>CCB</sub> , or GND			±100	mA
Junction temperature, T <sub>J</sub>			150	°C
Storage temperature, T <sub>stg</sub>		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 6.2 ESD Ratings

			VALUE	UNIT
.,		Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins, A Port <sup>(1)</sup>	±2500	V
	Electrostatic	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins, B Port <sup>(1)</sup>	±8000	٧
V <sub>(ESD)</sub>	discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 (2)	±1500	V
		250-V Machine Model (A115-A), all pins	±250	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

<sup>(2)</sup> The input and output negative-voltage ratings may be exceeded if the input and output current ratings are observed.

<sup>3)</sup> The value of V<sub>CCA</sub> and V<sub>CCB</sub> are provided in the recommended operating conditions table.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.



## 6.3 Recommended Operating Conditions

 $V_{\text{CCI}}$  is the supply voltage associated with the input port.  $V_{\text{CCO}}$  is the supply voltage associated with the output port.

				MIN	MAX	UNIT
$V_{CCA}$	Supply voltage <sup>(1)</sup>			1.65	3.6	V
$V_{CCB}$	Supply voltage			2.3	5.5	V
		A port I/Os	$V_{CCA} = 1.65 \text{ V to } 1.95 \text{ V}$ $V_{CCB} = 2.3 \text{ V to } 5.5 \text{ V}$	V <sub>CCI</sub> - 0.2	V <sub>CCI</sub>	V
V	High-level	A-port I/Os	$V_{CCA} = 1.65 \text{ V to } 3.6 \text{ V}$ $V_{CCB} = 2.3 \text{ V to } 5.5 \text{ V}$	V <sub>CCI</sub> - 0.4	V <sub>CCI</sub>	V
$V_{IH}$	input voltage	B-port I/Os	$V_{CCA} = 1.65 \text{ V to } 3.6 \text{ V}$ $V_{CCB} = 2.3 \text{ V to } 5.5 \text{ V}$	V <sub>CCI</sub> - 0.4	V <sub>CCI</sub>	V
		OE input	V <sub>CCA</sub> = 1.65 V to 3.6 V V <sub>CCB</sub> = 2.3 V to 5.5 V	V <sub>CCA</sub> × 0.65	5.5	V
		A-port I/Os	V <sub>CCA</sub> = 1.65 V to 3.6 V V <sub>CCB</sub> = 2.3 V to 5.5 V	0	0.15	V
$V_{IL}^{(2)}$	Low-level input voltage	B-port I/Os	$V_{CCA} = 1.65 \text{ V to } 3.6 \text{ V}$ $V_{CCB} = 2.3 \text{ V to } 5.5 \text{ V}$	0	0.15	V
		OE input	V <sub>CCA</sub> = 1.65 V to 3.6 V V <sub>CCB</sub> = 2.3 V to 5.5 V	0	V <sub>CCA</sub> × 0.35	V
		A-port I/Os push-pull driving	V <sub>CCA</sub> = 1.65 V to 3.6 V V <sub>CCB</sub> = 2.3 V to 5.5 V		10	ns/V
Δt/Δν	Input transition rise or fall rate	B-port I/Os push-pull driving	V <sub>CCA</sub> = 1.65 V to 3.6 V V <sub>CCB</sub> = 2.3 V to 5.5 V		10	ns/V
		Control input	V <sub>CCA</sub> = 1.65 V to 3.6 V V <sub>CCB</sub> = 2.3 V to 5.5 V		10	ns/V
T <sub>A</sub>	Operating free-air to	emperature		-40	85	°C

## 6.4 Thermal Information

				TXS0102			
	THERMAL METRIC <sup>(1)</sup>	DCT	DCU	DQE	DQM	YZP	UNIT
		8 PINS	8 PINS	8 PINS	8 PINS	8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	182.6	199.1	199.3	239.3	105.8	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	113.3	72.4	26.4	106.7	1.6	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	94.9	77.8	78.6	130.4	10.8	°C/W
ΨЈТ	Junction-to-top characterization parameter	39.4	6.2	5.9	8.2	3.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	93.9	77.4	78.0	130.2	10.8	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	_	_	_	_	_	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application

 $V_{CCA}$  must be less than or equal to  $V_{CCB}$ , and  $V_{CCA}$  must not exceed 3.6 V. The maximum  $V_{IL}$  value is provided to ensure that a valid  $V_{OL}$  is maintained. The  $V_{OL}$  value is  $V_{IL}$  plus the voltage drop across the passgate transistor.



#### 6.5 Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)<sup>(1)</sup> (2) (3)

_	ADAMETED	TEST CONDITIONS	V	V	T,	4 = 25°	C	$T_A = -40^{\circ}C$	to +8	5°C	UNIT
P	ARAMETER	TEST CONDITIONS	V <sub>CCA</sub>	V <sub>CCB</sub>	MIN	TYP	MAX	MIN	TYP	MAX	UNII
V <sub>OHA</sub>	Port A output high voltage	$I_{OH} = -20 \mu A$ $V_{IB} \ge V_{CCB} - 0.4 V$	1.65 V to 3.6 V	2.3 V to 5.5 V				V <sub>CCA</sub> × 0.67			V
V <sub>OLA</sub>	Port A output low voltage	$I_{OL} = 1 \text{ mA}$ $V_{IB} \le 0.15 \text{ V}$	1.65 V to 3.6 V	2.3 V to 5.5 V						0.4	V
V <sub>OHB</sub>	Port B output high voltage		1.65 V to 3.6 V	2.3 V to 5.5 V				V <sub>CCB</sub> × 0.67			V
V <sub>OLB</sub>	Port B output low voltage		1.65 V to 3.6 V	2.3 V to 5.5 V						0.4	V
ı	Input leakage current	OE	1.65 V to 3.6 V	2.3 V to 5.5 V			±1			±2	
	Partial power	A port	0 V	0 V to 5.5 V			±1			±2	
off	down current	B port	0 V to 3.6 V	0 V			±1			±2	μΑ
OZ	High-impedance state output current	A or B port	1.65 V to 3.6 V	2.3 V to 5.5 V			±1			±2	
			1.65 V to V <sub>CCB</sub>	2.3 V to 5.5 V						2.4	+
CCA	V <sub>CCA</sub> supply current	$V_I = V_O = open$ $I_O = 0$	3.6 V	0 V						2.2	
	odifont	10 = 0	0 V	5.5 V						-1	
			1.65 V to V <sub>CCB</sub>	2.3 V to 5.5 V						12	
ССВ	V <sub>CCB</sub> supply current	$V_I = V_O = open$ $I_O = 0$	3.6 V	0 V						-1	μΑ
	odironi	10 – 0	0 V	5.5 V						1	
CCA + CCB	Combined supply current	$V_I = V_{CCI}$ or GND $I_O = 0$	1.65 V to V <sub>CCB</sub>	2.3 V to 5.5 V						14.4	μΑ
Cı	Input capacitance	OE	3.3 V	3.3 V		2.5				3.5	pF
	Input-to-output	A or B port	3.3 V	3.3 V	/ 10						
$C_{io}$	internal	A port				5			6		pF
	capacitance	B port				6			7.5		

 $<sup>\</sup>begin{array}{ll} \hbox{(1)} & V_{CCI} \text{ is the $V_{CC}$ associated with the input port.} \\ \hbox{(2)} & V_{CCO} \text{ is the $V_{CC}$ associated with the output port.} \\ \hbox{(3)} & V_{CCA} \text{ must be less than or equal to $V_{CCB}$, and $V_{CCA}$ must not exceed 3.6 V.} \\ \end{array}$ 



## 6.6 Timing Requirements: V<sub>CCA</sub> = 1.8 V ±0.15 V

_	<u> </u>	007							
			V <sub>CCB</sub> = 2.5 V ±	$V_{CCB} = 2.5 V \pm 0.2 V$		$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		$V_{CC} = 5 V \pm 0.5 V$	
			MIN	MAX	MIN	MAX	MIN	MAX	UNIT
	Data sata	Push-pull driving		21		22		24	Mana
	Data rate	Open-drain driving		2		2		2	Mbps
t <sub>v</sub>		Push-pull driving (data inputs)	47		45		41		
	Pulse duration	Open-drain driving (data inputs)	500		500		500		ns

## 6.7 Timing Requirements: $V_{CCA} = 2.5 \text{ V} \pm 0.2 \text{ V}$

	<u> </u>	COA							
			V <sub>CCB</sub> = 2.5 V ±	$V_{CC} = 3.3 V \pm 0.3 V$		± 0.3 V	$V_{CC} = 5 V \pm 0.5 V$		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	UNII
	Data rate	Push-pull driving		20		22		24	Mbps
	Dala fale	Open-drain driving		2		2		2	
t	W	Push-pull driving (data inputs)	50		45		41		20
	Pulse duration	Open-drain driving (data inputs)	500		500		500		ns

## 6.8 Timing Requirements: $V_{CCA} = 3.3 \text{ V} \pm 0.3 \text{ V}$

			$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		$V_{CC} = 5 V \pm 0.5 V$	V	UNIT	
			MIN	MAX	MIN	MAX	UNIT	
	Data rata	Push-pull driving		23		24	Mhna	
	Data rate	Open-drain driving		2		2	Mbps	
t <sub>w</sub>	Pulse duration	Push-pull driving (data inputs)	43		41			
		Open-drain driving (data inputs)	500		500		ns	



# 6.9 Switching Characteristics: $V_{CCA} = 1.8 \text{ V} \pm 0.15 \text{ V}$

over operating free-air temperature range (unless otherwise noted)

ъ.	DAMETED	TEC	T CONDITIONS	V <sub>CCB</sub> = 2.5 V	±0.2 V	V <sub>CCB</sub> = 3.3 V	±0.2 V	$V_{CCB} = 3.3 \text{ V}$	±0.2 V	UNIT
PA	RAMETER	IES	T CONDITIONS	MIN	MAX	MIN	MAX	MIN	MAX	UNII
t <sub>PHL</sub>	Propagation delay time high-to-low	A-to-B	Push-pull driving		5.3		5.4		6.8	ns
	output		Open-drain driving	2.3	8.8	2.4	9.6	2.6	10	
$t_{PLH}$	Propagation		Push-pull driving		6.8		7.1		7.5	
	delay time low-to-high output	A-to-B	Open-drain driving	45	260	36	208	27	198	ns
$t_{PHL}$	Propagation		Push-pull driving		4.4		4.5		4.7	
	delay time high-to-low output	B-to-A	Open-drain driving	1.9	5.3	1.1	4.4	1.2	4	ns
t <sub>PLH</sub>	Propagation		Push-pull driving		5.3		4.5		0.5	
	delay time low-to-high output	B-to-A	Open-drain driving	45	175	36	140	27	102	
t <sub>en</sub>	Enable time	OE-to-A o	OE-to-A or B		200		200		200	ns
t <sub>dis</sub>	Disable time	OE-to-A o	r B		50		40		35	ns
$t_{\text{rA}}$	Input rise	A port	Push-pull driving	3.2	9.5	2.3	9.3	2	7.6	ns
	time	rise time	Open-drain driving	38	165	30	132	22	95	113
$t_{rB}$	Input rise	B port	Push-pull driving	4	10.8	2.7	9.1	2.7	7.6	ns
	time	rise time	Open-drain driving	34	145	23	106	10	58	115
$t_fA$	Input fall time	A port	Push-pull driving	2	5.9	1.9	6	1.7	13.3	ns
	input iaii tiine	fall time	Open-drain driving	4.4	6.9	4.3	6.4	4.2	6.1	115
$t_{fB}$	Input fall time	B port	Push-pull driving	2.9	13.8	2.8	16.2	2.8	16.2	no
	input fail time	fall time	Open-drain driving	6.9	13.8	7.5	16.2	7	16.2	ns
t <sub>SK(O)</sub>	Skew (time), output	Channel -to- channel skew			0.7		0.7		0.7	ns
	Maximum		Push-pull driving	21		22		24		Mbps
	data rate		Open-drain driving	2		2		2		Minh2



# 6.10 Switching Characteristics: $V_{CCA} = 2.5 \text{ V} \pm 0.2 \text{ V}$

over operating free-air temperature range (unless otherwise noted)

DADAMETED		TEST OF	NDITIONS	V <sub>CCB</sub> = 2.5 V	±0.2 V	V <sub>CCB</sub> = 3.3 \	/ ±0.3 V	V <sub>CCB</sub> = 5 V :	V <sub>CCB</sub> = 5 V ± 0.5 V			
PA	RAMETER	TEST CC	NDITIONS	MIN	MAX	MIN	MAX	MIN	MAX	UNIT		
	Propagation		Push-pull driving		3.2		3.7		3.8			
t <sub>PHL</sub>	delay time high-to-low output	A-to-B	Open-drain driving	1.7	6.3	2	6	2.1	5.8	ns		
	Propagation		Push-pull driving		3.5		4.1		4.4			
t <sub>PLH</sub>	delay time PLH low-to-high output A-to-B		Open-drain driving	43	250	36	206	27	190	ns		
	Propagation		Push-pull driving		3		3.6		4.3			
t <sub>PHL</sub>	delay time high-to-low output	B-to-A	Open-drain driving	1.8	4.7	2.6	4.2	1.2	4	ns		
	Propagation		Push-pull driving		2.5		1.6		1			
t <sub>PLH</sub>	delay time low-to-high output	B-to-A	Open-drain driving	44	170	37	140	27	103	ns		
t <sub>en</sub>	Enable time	OE-to-A or B			200		200		200	ns		
t <sub>dis</sub>	Disable time	OE-to-A or B			50		40		35	ns		
	Lancia de la		Push-pull driving	2.8	7.4	2.6	6.6	1.8	5.6			
t <sub>rA</sub>	A lnput rise time A port rise time		Open-drain driving	3	149	28	121	24	89	ns		
	Input rise			Push-pull driving	3.2	8.3	2.9	7.2	2.4	6.1		
t <sub>rB</sub>	time	B port rise time	Open-drain driving	35	151	24	112	12	64	ns		
			Push-pull driving	1.9	5.7	1.9	5.5	1.8	5.3			
t <sub>fA</sub>	Input fall time	A port fall time	Open-drain driving	4.4	6.9	4.3	6.2	4.2	5.8	ns		
			Push-pull driving	2.2	7.8	2.4	6.7	2.6	6.6			
t <sub>fB</sub>	Input fall time	B port fall time	Open-drain driving	5.1	8.8	5.4	9.4	5.4	10.4	ns		
t <sub>SK(O)</sub>	Skew (time), output	Channel-to-chan	nel skew		0.7		0.7		0.7	ns		
	Maximum		Push-pull driving	20		22		24				
	data rate		Open-drain driving	2		2		2		Mbps		



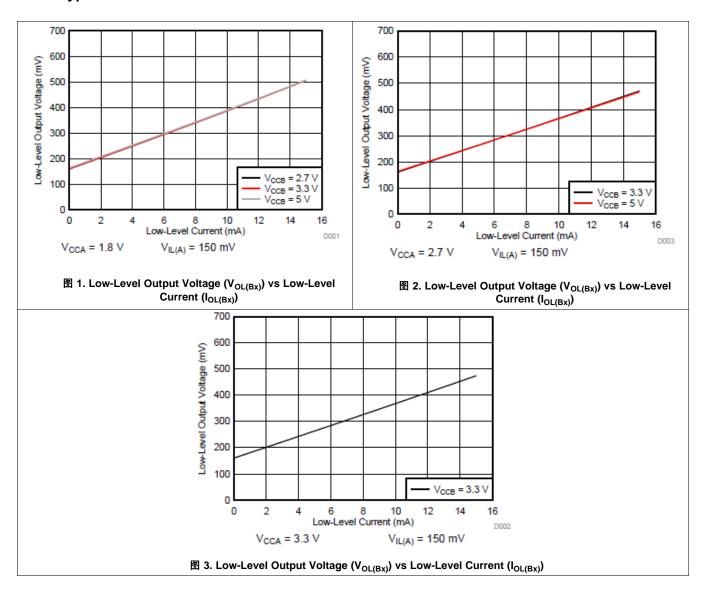
# 6.11 Switching Characteristics: $V_{CCA} = 3.3 \text{ V} \pm 0.3 \text{ V}$

over operating free-air temperature range (unless otherwise noted)

DADAMETED		TECT	CONDITIONS	V <sub>CCB</sub> = 3.3 V ±	0.2 V	$V_{CCB} = 5 V \pm 0$	$V_{CCB} = 5 V \pm 0.5 V$				
PA	RAMETER	IESI	CONDITIONS	MIN	MAX	MIN	MAX	UNIT			
	Propagation		Push-pull driving		2.4		3.1				
t <sub>PHL</sub>	delay time high-to-low output	A-to-B	Open-drain driving	1.3	4.2	1.4	4.6	ns			
	Propagation		Push-pull driving		4.2		4.4				
t <sub>PLH</sub>	delay time low-to-high output	A-to-B	Open-drain driving	36	204	28	165	ns			
	Propagation		Push-pull driving		2.5		3.3				
t <sub>PHL</sub>	delay time high-to-low output	B-to-A	Open-drain driving	1	124	1	97	ns			
	Propagation delay time		Push-pull driving		2.5		2.6				
t <sub>PLH</sub>		B-to-A	Open-drain driving	3	139	3	105	ns			
t <sub>en</sub>	Enable time	OE-to-A or B			200		200	ns			
t <sub>dis</sub>	Disable time	OE-to-A or B			40		35	ns			
+ .	Input rise	A port rise time	Push-pull driving	2.3	5.6	1.9	4.8	ns			
t <sub>rA</sub>	time	A port rise time	Open-drain driving	25	116	19	85	115			
t _	Input rise	B port rise time	Push-pull driving	2.5	6.4	2.1	MAX 3.1 4.6 4.4 165 3.3 97 2.6 105 200 35 4.8	ns			
t <sub>rB</sub>	time	b port rise time	Open-drain driving	26	116	14	72	115			
t <sub>fA</sub>	Input fall time	A port fall time	Push-pull driving	2	5.4	1.9	5	ns			
чA	input iaii time	A port fail time	Open-drain driving	4.3	6.1	4.2	5.7	113			
<b>+</b>	B Input fall time B port fall tin	B port fall time	Push-pull driving	2.3	7.4	2.4	7.6	ns			
t <sub>fB</sub>		D port fail time	Open-drain driving	5	7.6	4.8	8.3				
t <sub>SK(O)</sub>	Skew (time), output	Channel-to-chann	el skew		0.7		0.7	ns			
	Maximum		Push-pull driving	23		24		Mbps			
	data rate		Open-drain driving	2		2		Minha			



## 6.12 Typical Characteristics





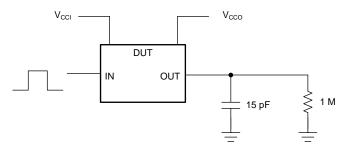
#### 7 Parameter Measurement Information

Unless otherwise noted, all input pulses are supplied by generators having the following characteristics:

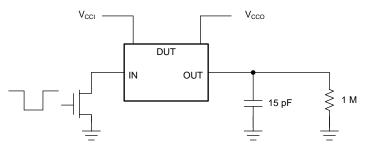
- PRR 10 MHz
- $Z_0 = 50 \text{ W}$
- dv/dt ≥ 1 V/ns

#### 注

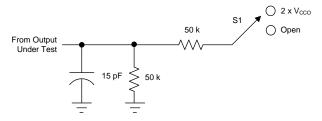
All parameters and waveforms are not applicable to all devices.



# 图 4. Data Rate, Pulse Duration, Propagation Delay, Output Rise And Fall Time Measurement Using A Push-Pull Driver



# 图 5. Data Rate, Pulse Duration, Propagation Delay, Output Rise And Fall Time Measurement Using An Open-Drain Driver



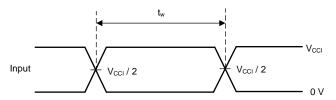
#### 图 6. Load Circuit For Enable / Disable Time Measurement

#### 表 1. Switch Configuration For Enable / Disable Timing

TEST	S1
$t_{PZL}^{(1)}, t_{PLZ}^{(2)}$	2 × V <sub>CCO</sub>
t <sub>PHZ</sub> <sup>(2)</sup> , t <sub>PZH</sub> <sup>(1)</sup>	Open

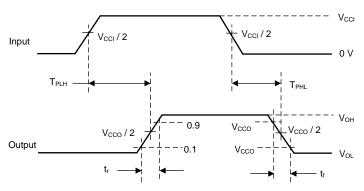
- (1) t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- (2) t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.





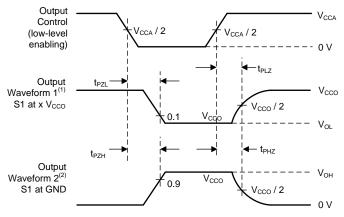
(1) All input pulses are measured one at a time, with one transition per measurement.

#### 图 7. Voltage Waveforms Pulse Duration



A. All input pulses are measured one at a time, with one transition per measurement.

## 图 8. Voltage Waveforms Propagation Delay Times



- (1) Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output
- (2) Waveform 2 is for an output with internal conditions such that the ouput is high, except when disabled by the output control.

## 图 9. Voltage Waveforms Enable And Disable Times

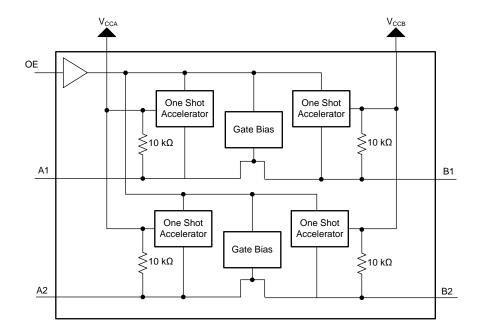


## 8 Detailed Description

#### 8.1 Overview

The TXS0102 device is a directionless voltage-level translator specifically designed for translating logic voltage levels. The A port is able to accept I/O voltages ranging from 1.65 V to 3.6 V, while the B port can accept I/O voltages from 2.3 V to 5.5 V. The device is a pass-gate architecture with edge-rate accelerators (one-shots) to improve the overall data rate. 10-k $\Omega$  pullup resistors, commonly used in open-drain applications, have been conveniently integrated so that an external resistor is not needed. While this device is designed for open-drain applications, the device can also translate push-pull CMOS logic outputs.

## 8.2 Functional Block Diagram





#### 8.3 Feature Description

#### 8.3.1 Architecture

The TXS0102 architecture (see Figure 10) is an auto-direction-sensing based translator that does not require a direction-control signal to control the direction of data flow from A to B or from B to A.

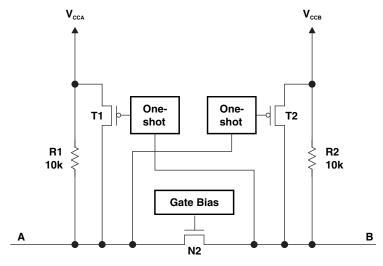


图 10. Architecture of a TXS0102 Cell

These two bidirectional channels independently determine the direction of data flow without a direction-control signal. Each I/O pin can be automatically reconfigured as either an input or an output, which is how this auto-direction feature is realized.

The TXS0102 device is part of TI's "Switch" type voltage translator family and employs two key circuits to enable this voltage translation:

- 1) An N-channel pass-gate transistor topology that ties the A-port to the B-port and
- 2) Output one-shot (O.S.) edge-rate accelerator circuitry to detect and accelerate rising edges on the A or B ports

For bidirectional voltage translation, pull-up resistors are included on the device for dc current sourcing capability. The  $V_{GATE}$  gate bias of the N-channel pass transistor is set at approximately one threshold voltage ( $V_T$ ) above the  $V_{CC}$  level of the low-voltage side. Data can flow in either direction without guidance from a control signal.

The O.S. rising-edge rate accelerator circuitry speeds up the output slew rate by monitoring the input edge for transitions, helping maintain the data rate through the device. During a low-to-high signal rising edge, the O.S. circuits turn on the PMOS transistors (T1, T2) to increase the current drive capability of the driver for approximately 30 ns or 95% of the input edge, whichever occurs first. This edge-rate acceleration provides high ac drive by bypassing the internal 10-k $\Omega$  pull-up resistors during the low-to-high transition to speed up the signal. The output resistance of the driver is decreased to approximately  $50~\Omega$  to  $70~\Omega$  during this acceleration phase. To minimize dynamic  $I_{CC}$  and the possibility of signal contention, the user should wait for the O.S. circuit to turn off before applying a signal in the opposite direction. The worst-case duration is equal to the minimum pulse-width number provided in the *Timing Requirements* section of this data sheet.



## Feature Description (接下页)

#### 8.3.2 Input Driver Requirements

The continuous dc-current "sinking" capability is determined by the external system-level open-drain (or push-pull) drivers that are interfaced to the TXS0102 I/O pins. Since the high bandwidth of these bidirectional I/O circuits is used to facilitate this fast change from an input to an output and an output to an input, they have a modest dc-current "sourcing" capability of hundreds of micro-Amps, as determined by the internal  $10\text{-k}\Omega$  pullup resistors.

The fall time ( $t_{fA}$ ,  $t_{fB}$ ) of a signal depends on the edge-rate and output impedance of the external device driving TXS0102 data I/Os, as well as the capacitive loading on the data lines.

Similarly, the  $t_{PHL}$  and max data rates also depend on the output impedance of the external driver. The values for  $t_{fA}$ ,  $t_{fB}$ ,  $t_{PHL}$ , and maximum data rates in the data sheet assume that the output impedance of the external driver is less than 50  $\Omega$ .

#### 8.3.3 Output Load Considerations

TI recommends careful PCB layout practices with short PCB trace lengths to avoid excessive capacitive loading and to ensure that proper O.S. triggering takes place. PCB signal trace-lengths should be kept short enough such that the round trip delay of any reflection is less than the one-shot duration. This improves signal integrity by ensuring that any reflection sees a low impedance at the driver. The O.S. circuits have been designed to stay on for approximately 30 ns. The maximum capacitance of the lumped load that can be driven also depends directly on the one-shot duration. With very heavy capacitive loads, the one-shot can time-out before the signal is driven fully to the positive rail. The O.S. duration has been set to best optimize trade-offs between dynamic ICC, load driving capability, and maximum bit-rate considerations. Both PCB trace length and connectors add to the capacitance that the TXS0102 device output sees, so it is recommended that this lumped-load capacitance be considered to avoid O.S. retriggering, bus contention, output signal oscillations, or other adverse system-level affects.

#### 8.3.4 Enable and Disable

The TXS0102 device has an OE input that is used to disable the device by setting OE low, which places all I/Os in the Hi-Z state. The disable time  $(t_{dis})$  indicates the delay between the time when OE goes low and when the outputs are disabled (Hi-Z). The enable time  $(t_{en})$  indicates the amount of time the user must allow for the one-shot circuitry to become operational after OE is taken high.

#### 8.3.5 Pullup or Pulldown Resistors on I/O Lines

Each A-port I/O has an internal 10-k $\Omega$  pullup resistor to  $V_{CCA}$ , and each B-port I/O has an internal 10-k $\Omega$  pullup resistor to  $V_{CCB}$ . If a smaller value of pullup resistor is required, an external resistor must be added from the I/O to  $V_{CCB}$  (in parallel with the internal 10-k $\Omega$  resistors). Adding lower value pull-up resistors will effect  $V_{OL}$  levels, however. The internal pull-ups of the TXS0102 are disabled when the OE pin is low.

#### 8.4 Device Functional Modes

The device has two functional modes, enabled and disabled. To disable the device set the OE input low, which places all I/Os in a high impedance state. Setting the OE input high will enable the device.



## 9 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 9.1 Application Information

The TXS0102 device can be used to bridge the digital-switching compatibility gap between two voltage nodes to successfully interface logic threshold levels found in electronic systems. It should be used in a point-to-point topology for interfacing devices or systems operating at different interface voltages with one another. Its primary target application use is for interfacing with open-drain drivers on the data I/Os such as I<sup>2</sup>C or 1-wire, where the data is bidirectional and no control signal is available. The device can also be used in applications where a push-pull driver is connected to the data I/Os, but the TXB0102 might be a better option for such push-pull applications.

## 9.2 Typical Application

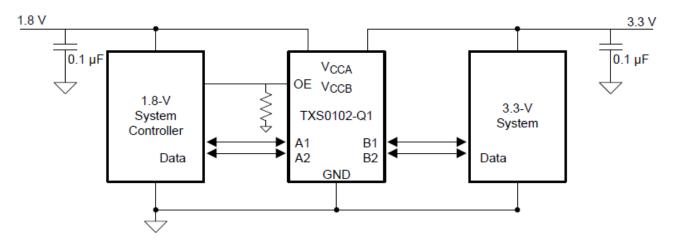


图 11. Typical Application Circuit

#### 9.2.1 Design Requirements

For this design example, use the parameters listed in Table 3. And make sure the V<sub>CCA</sub> ≤ V<sub>CCB</sub>.

#### 表 2. Design Parameters

DESIGN PARAMETER	EXAMPLE VALUE
Input voltage range	1.65 to 3.6 V
Output voltage range	2.3 to 5.5 V



#### 9.2.2 Detailed Design Procedure

To begin the design process, determine the following:

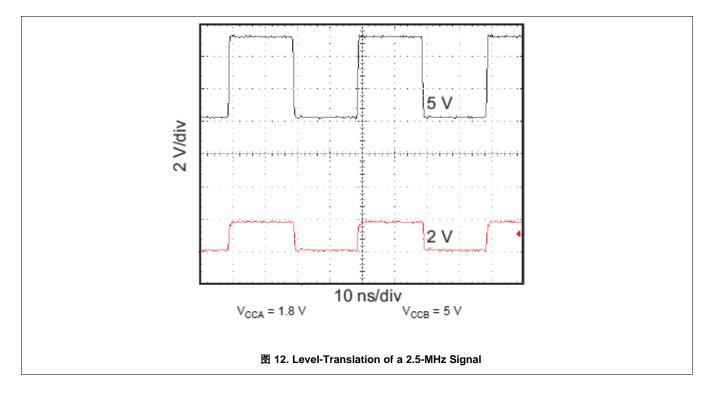
- Input voltage range
  - Use the supply voltage of the device that is driving the TXS0102 device to determine the input voltage range. For a valid logic high the value must exceed the VIH of the input port. For a valid logic low the value must be less than the VIL of the input port.
- Output voltage range
  - Use the supply voltage of the device that the TXS0102 device is driving to determine the output voltage range.
  - The TXS0102 device has 10-k $\Omega$  internal pullup resistors. External pullup resistors can be added to reduce the total RC of a signal trace if necessary.
- An external pull down resistor decreases the output VOH and VOL. Use Equation 1 to calculate the VOH as a result of an external pull down resistor.

$$V_{OH} = V_{CCx} \times R_{PD} / (R_{PD} + 10 \text{ k}\Omega)$$

Where:

- $\bullet$  V<sub>CCx</sub> is the supply voltage on either V<sub>CCA</sub> or V<sub>CCB</sub>
- RPD is the value of the external pull down resistor

## 9.2.3 Application Curves





## 10 Power Supply Recommendations

During operation, ensure that  $V_{CCA} \le V_{CCB}$  at all times. The sequencing of each power supply will not damage the device during the power up operation, so either power supply can be ramped up first. The output-enable (OE) input circuit is designed so that it is supplied by  $V_{CCA}$  and when the (OE) input is low, all outputs are placed in the high-impedance state. To ensure the high-impedance state of the outputs during power up or power down, the OE input pin must be tied to GND through a pulldown resistor and must not be enabled until  $V_{CCA}$  and  $V_{CCB}$  are fully ramped and stable. The minimum value of the pulldown resistor to ground is determined by the current-sourcing capability of the driver.

## 11 Layout

#### 11.1 Layout Guidelines

To ensure reliability of the device, the following common printed-circuit board layout guidelines are recommended:

- Bypass capacitors should be used on power supplies and should be placed as close as possible to the  $V_{CCA}$ ,  $V_{CCB}$  pin, and  $G_{ND}$  pin.
- Short trace lengths should be used to avoid excessive loading.
- PCB signal trace-lengths must be kept short enough so that the round-trip delay of any reflection is less than the one-shot duration, approximately 30 ns, ensuring that any reflection encounters low impedance at the source driver.

## 11.2 Layout Example

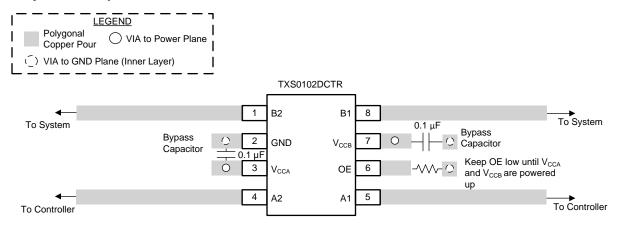


图 13. TXS0102 Layout Example



#### 12 器件和文档支持

#### 12.1 文档支持

#### 12.1.1 相关文档

请参阅如下相关文档:

- 德州仪器 (TI), 《使用 TXS-型转换器进行电压转换指南》应用手册
- 德州仪器 (TI), 《TXS 和 LSF 自动双向转换器件的 VOL 影响因素》应用手册
- 德州仪器 (TI), 《TXS、TXB 和 LSF 自动双向转换器的偏置要求》应用手册
- 德州仪器 (TI), 《上拉和下拉电阻器对 TXS 和 TXB 器件的影响》应用手册
- 德州仪器 (TI), 《逻辑简介》应用手册
- 德州仪器 (TI), 《TI 逻辑和线性产品指南》选择和解决方案指南
- 德州仪器 (TI), 《洗衣机解决方案指南》选择和解决方案指南
- 德州仪器 (TI), 《TI 智能手机解决方案指南》选择和解决方案指南

#### 12.2 接收文档更新通知

要接收文档更新通知,请导航至 Tl.com.cn 上的器件产品文件夹。单击右上角的通知我 进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

#### 12.3 社区资源

下列链接提供到 TI 社区资源的连接。链接的内容由各个分销商"按照原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的 《使用条款》。

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设计支持 TI 参考设计支持 可帮助您快速查找有帮助的 E2E 论坛、设计支持工具以及技术支持的联系信息。

#### 12.4 商标

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#### 12.5 静电放电警告



ESD 可能会损坏该集成电路。德州仪器 (TI) 建议通过适当的预防措施处理所有集成电路。如果不遵守正确的处理措施和安装程序,可能会损坏集成电路。

**ESD** 的损坏小至导致微小的性能降级,大至整个器件故障。 精密的集成电路可能更容易受到损坏,这是因为非常细微的参数更改都可能会导致器件与其发布的规格不相符。

#### 12.6 术语表

SLYZ022 — TI 术语表。

这份术语表列出并解释术语、缩写和定义。



# 13 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更,恕不另行通知,且 不会对此文档进行修订。如需获取此数据表的浏览器版本,请查阅左侧的导航栏。

30-Aug-2021

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#### **PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
TXS0102DCTR	ACTIVE	SM8	DCT	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFE (R, Z)	Samples
TXS0102DCTRE4	ACTIVE	SM8	DCT	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFE (R, Z)	Samples
TXS0102DCTT	ACTIVE	SM8	DCT	8	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFE (R, Z)	Samples
TXS0102DCTTE4	ACTIVE	SM8	DCT	8	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFE (R, Z)	Samples
TXS0102DCTTG4	ACTIVE	SM8	DCT	8	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFE (R, Z)	Samples
TXS0102DCUR	ACTIVE	VSSOP	DCU	8	3000	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	(FE, NFEQ, NFER) NZ	Samples
TXS0102DCURG4	ACTIVE	VSSOP	DCU	8	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFER	Samples
TXS0102DCUT	ACTIVE	VSSOP	DCU	8	250	RoHS & Green	NIPDAU   SN	Level-1-260C-UNLIM	-40 to 85	(FE, NFEQ, NFER) NZ	Samples
TXS0102DCUTG4	ACTIVE	VSSOP	DCU	8	250	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	NFER	Samples
TXS0102DQER	ACTIVE	X2SON	DQE	8	5000	RoHS & Green	NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	2H	Samples
TXS0102DQMR	ACTIVE	X2SON	DQM	8	3000	RoHS & Green	NIPDAU   NIPDAUAG	Level-1-260C-UNLIM	-40 to 85	2H (2H7, 2HR) (2HG, 2HH)	Samples
TXS0102YZPR	ACTIVE	DSBGA	YZP	8	3000	RoHS & Green	SNAGCU	Level-1-260C-UNLIM	-40 to 85	(2H, 2HN)	Samples

<sup>(1)</sup> The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW**: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

PACKAGE OPTION ADDENDUM

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RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF TXS0102:

Automotive: TXS0102-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects



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## TAPE AND REEL INFORMATION



## 

A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TXS0102DCTR	SM8	DCT	8	3000	177.8	12.4	3.45	4.4	1.45	4.0	12.0	Q3
TXS0102DCTR	SM8	DCT	8	3000	180.0	13.0	3.35	4.5	1.55	4.0	12.0	Q3
TXS0102DCTT	SM8	DCT	8	250	180.0	13.0	3.35	4.5	1.55	4.0	12.0	Q3
TXS0102DCUR	VSSOP	DCU	8	3000	180.0	9.0	2.25	3.4	1.0	4.0	8.0	Q3
TXS0102DCURG4	VSSOP	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
TXS0102DCUTG4	VSSOP	DCU	8	250	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
TXS0102DQER	X2SON	DQE	8	5000	180.0	8.4	1.2	1.6	0.55	4.0	8.0	Q1
TXS0102DQMR	X2SON	DQM	8	3000	180.0	8.4	1.57	2.21	0.59	4.0	8.0	Q1
TXS0102DQMR	X2SON	DQM	8	3000	180.0	9.5	1.4	2.0	0.5	4.0	8.0	Q1
TXS0102YZPR	DSBGA	YZP	8	3000	180.0	8.4	1.02	2.02	0.63	4.0	8.0	Q1



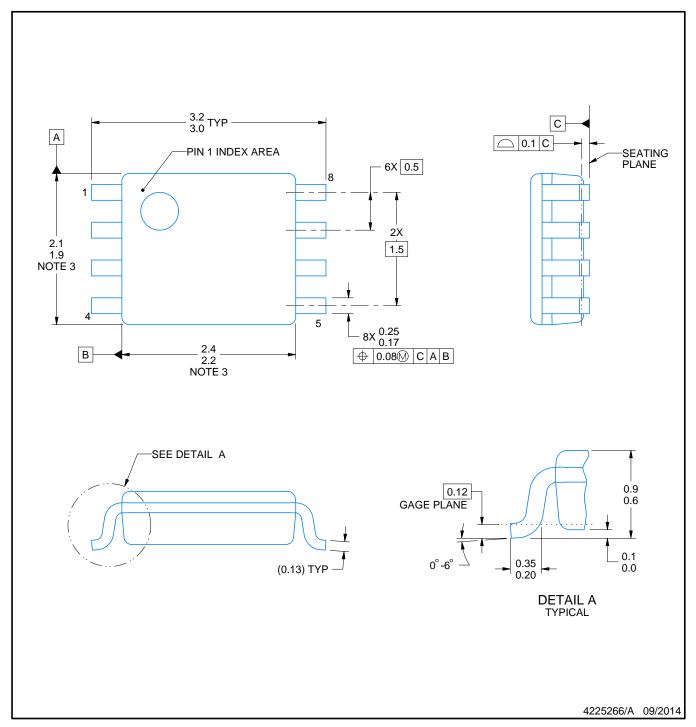
www.ti.com 1-Dec-2022



\*All dimensions are nominal

tili all'honolono aro nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TXS0102DCTR	SM8	DCT	8	3000	183.0	183.0	20.0
TXS0102DCTR	SM8	DCT	8	3000	182.0	182.0	20.0
TXS0102DCTT	SM8	DCT	8	250	182.0	182.0	20.0
TXS0102DCUR	VSSOP	DCU	8	3000	182.0	182.0	20.0
TXS0102DCURG4	VSSOP	DCU	8	3000	202.0	201.0	28.0
TXS0102DCUTG4	VSSOP	DCU	8	250	202.0	201.0	28.0
TXS0102DQER	X2SON	DQE	8	5000	202.0	201.0	28.0
TXS0102DQMR	X2SON	DQM	8	3000	202.0	201.0	28.0
TXS0102DQMR	X2SON	DQM	8	3000	184.0	184.0	19.0
TXS0102YZPR	DSBGA	YZP	8	3000	182.0	182.0	20.0





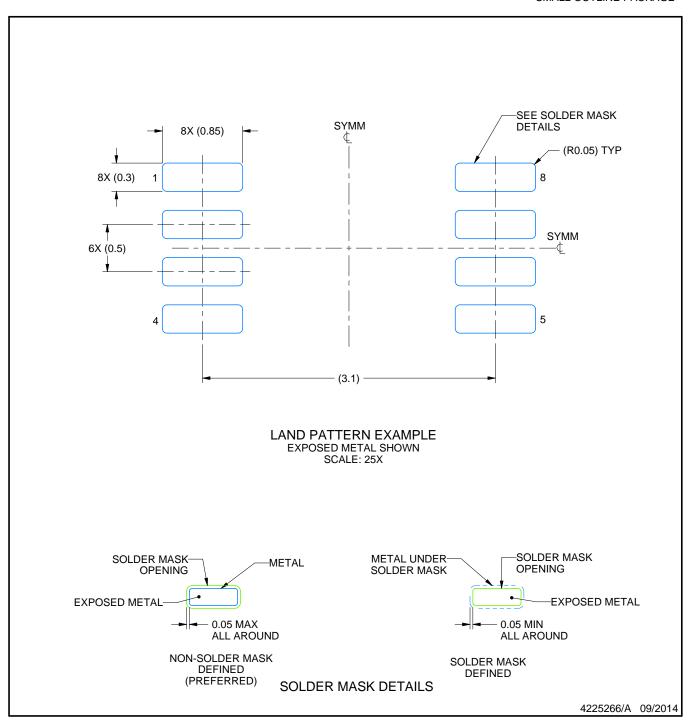
#### NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
  4. Reference JEDEC registration MO-187 variation CA.

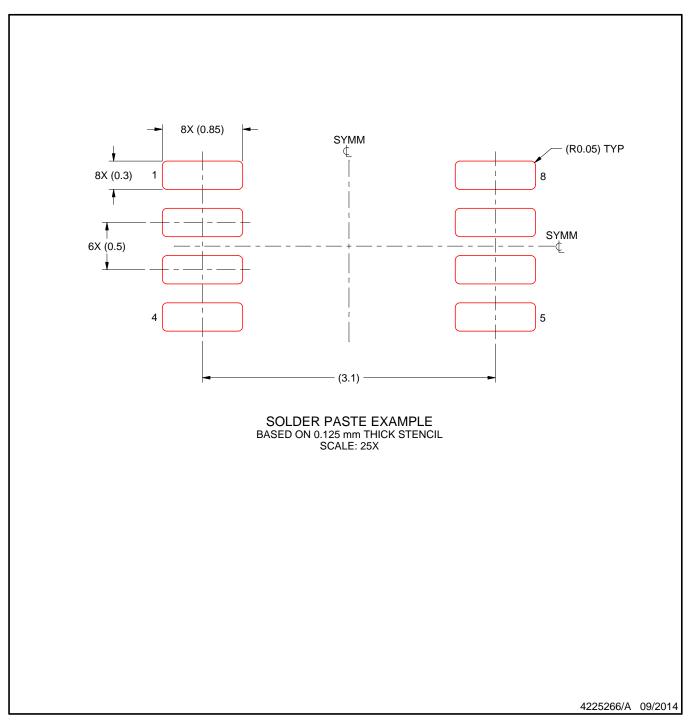




NOTES: (continued)

- 5. Publication IPC-7351 may have alternate designs.
- 6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



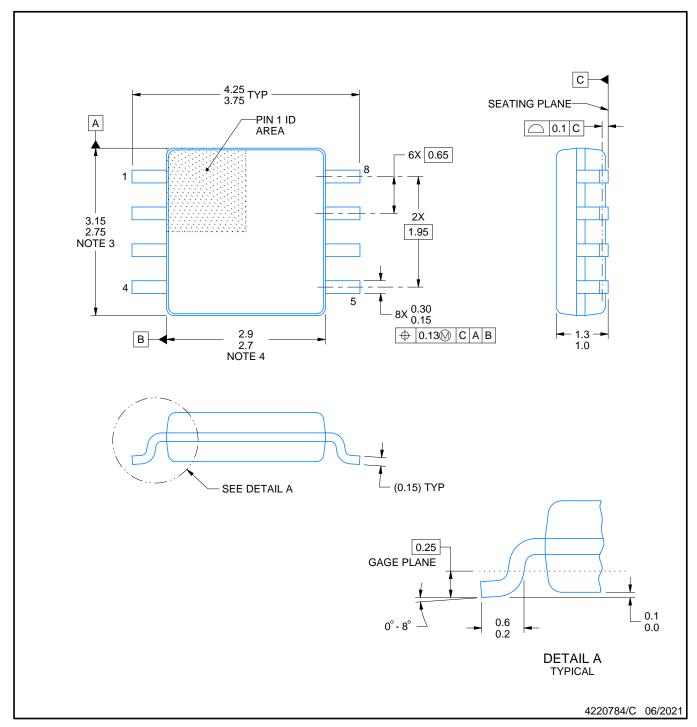


NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.







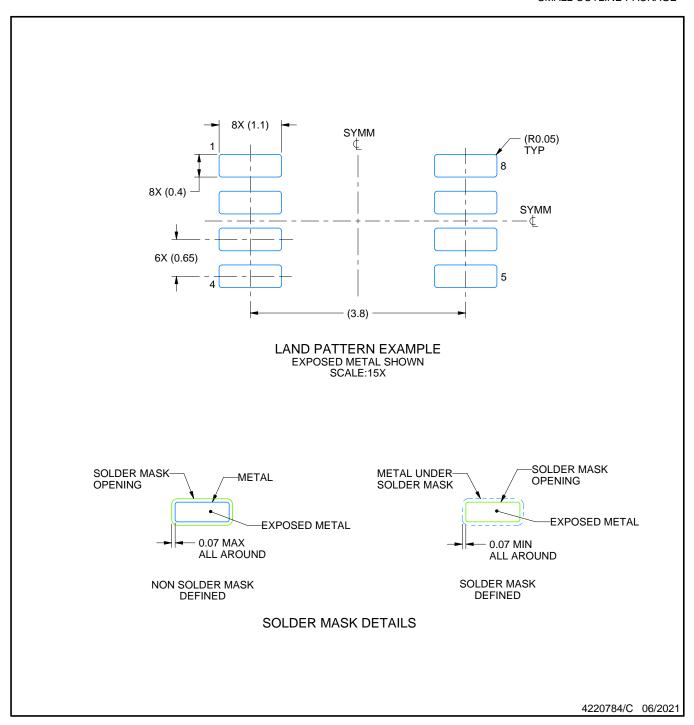
#### NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.

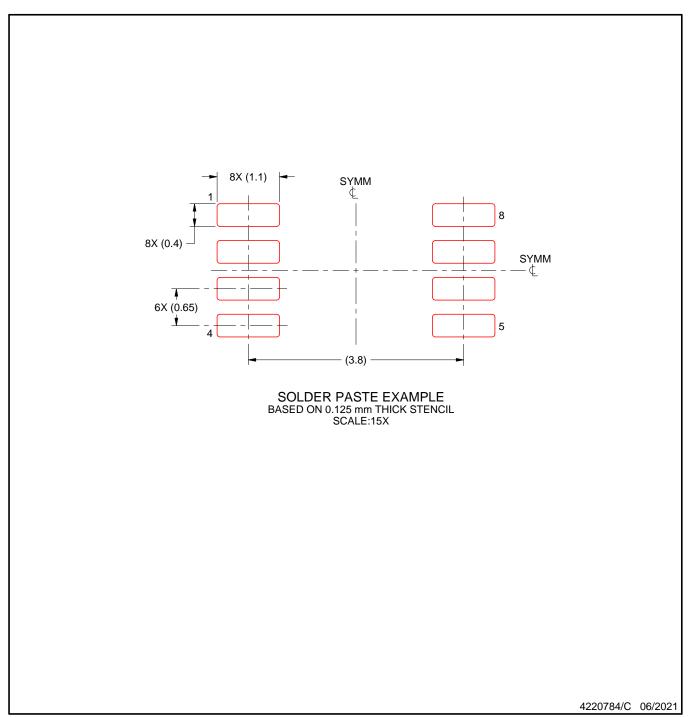




NOTES: (continued)

5. Publication IPC-7351 may have alternate designs.6. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

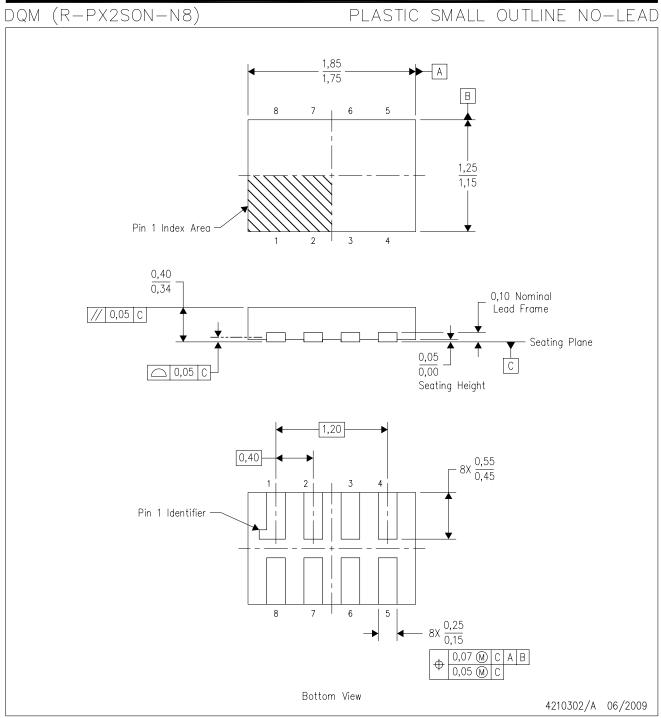




NOTES: (continued)

- 7. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 8. Board assembly site may have different recommendations for stencil design.





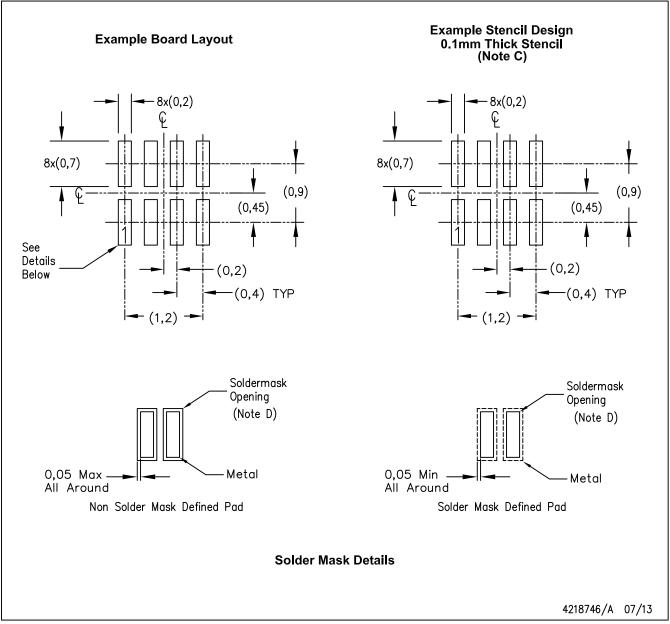
NOTES: All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.C. SON (Small Outline No-Lead) package configuration.



# DQM (R-PX2SON-N8)

# PLASTIC SMALL OUTLINE NO-LEAD



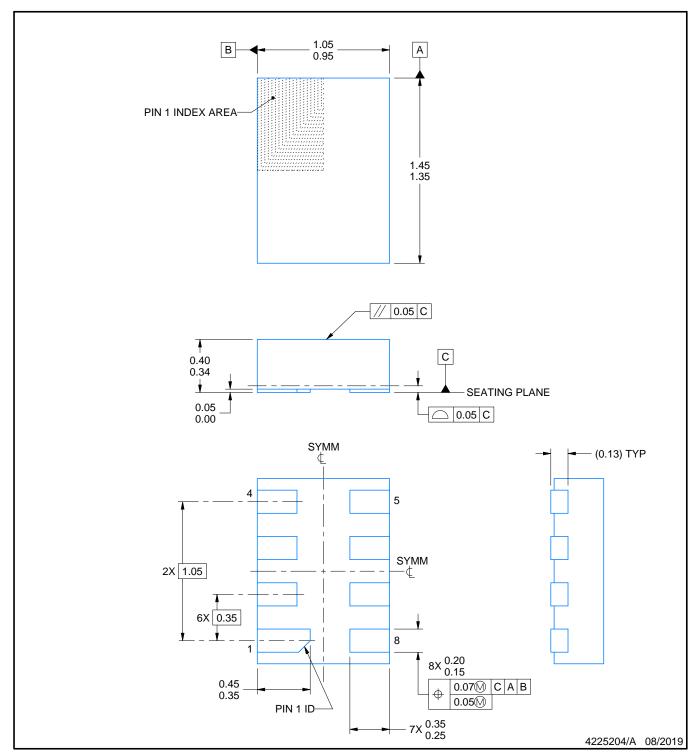
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- D. Customers should contact their board fabrication site for recommended solder mask tolerances.





PLASTIC SMALL OUTLINE - NO LEAD



#### NOTES:

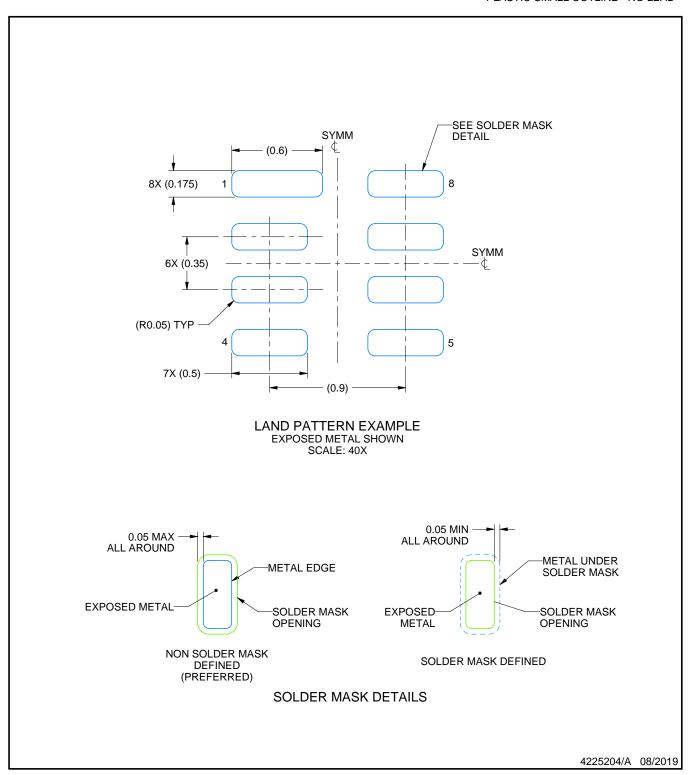
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This package complies to JEDEC MO-287 variation X2EAF.



PLASTIC SMALL OUTLINE - NO LEAD

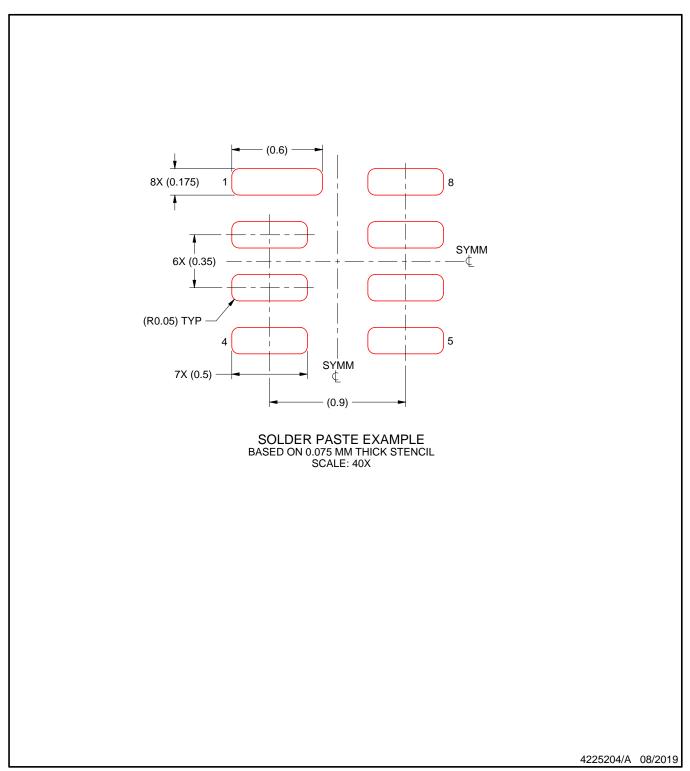


NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).



PLASTIC SMALL OUTLINE - NO LEAD



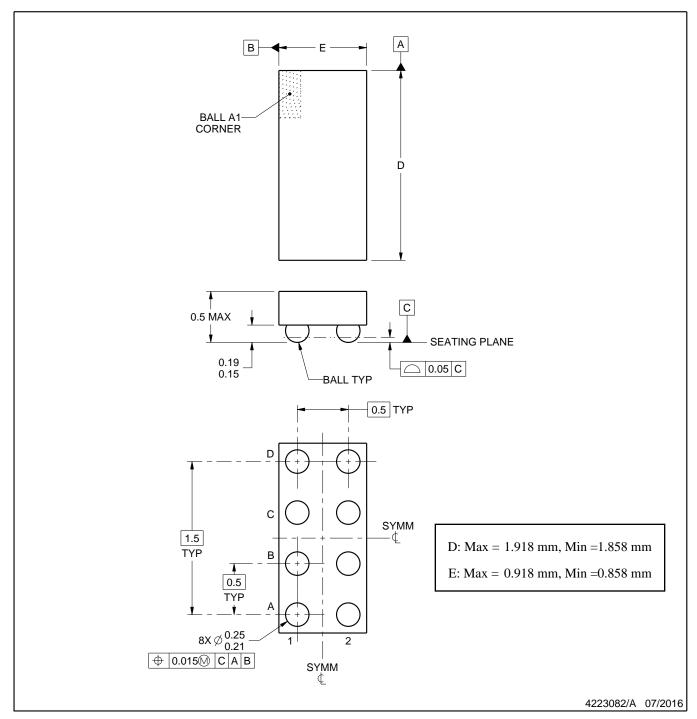
NOTES: (continued)

5. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.





DIE SIZE BALL GRID ARRAY

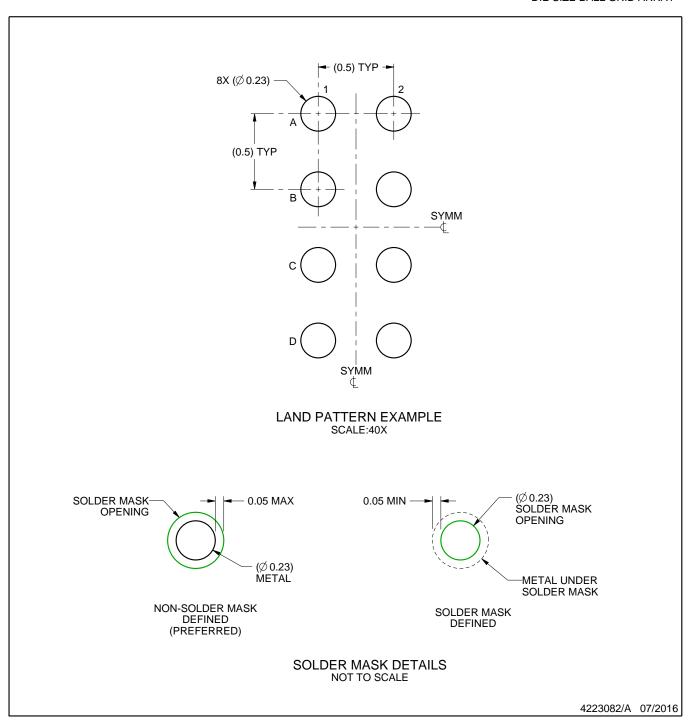


#### NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- 2. This drawing is subject to change without notice.



DIE SIZE BALL GRID ARRAY

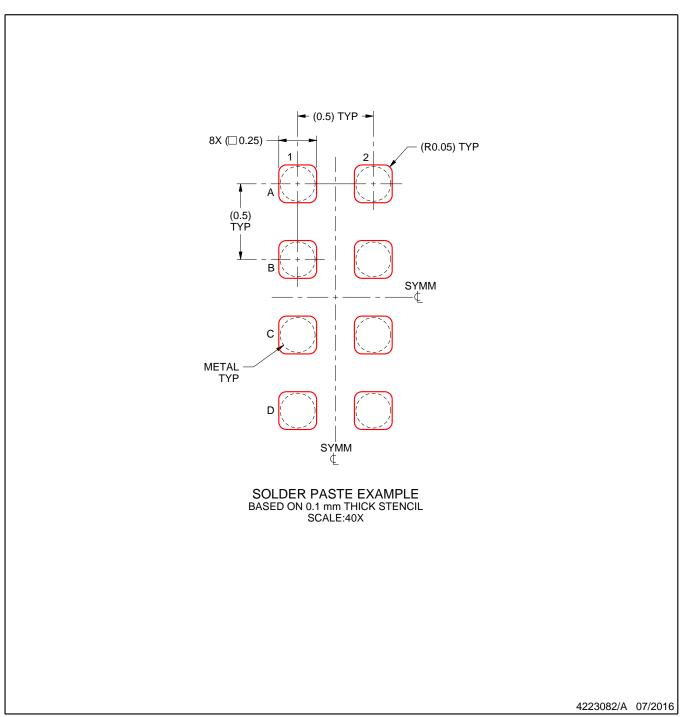


NOTES: (continued)

3. Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For more information, see Texas Instruments literature number SNVA009 (www.ti.com/lit/snva009).



DIE SIZE BALL GRID ARRAY



NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.



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